



A DOVER COMPANY



POGOPLUS®

▼ POGOPLUS TECHNOLOGY

ECT POGO<sup>s</sup>®

SELECT BY TEST CENTER

SELECT BY APPLICATION

- ▼ LOADED PCB
- ▼ BARE PCB
- ▼ WIRE HARNESS
- ▼ TEST SYSTEM INTERFACE
- ▼ HIGH CURRENT
- ▼ HIGH FREQUENCY
- ▼ IC TEST PROBES
- ▼ BATTERY/PORTABLE
- ▼ SEMICONDUCTOR
- ▼ GENERAL PURPOSE

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CUSTOM PROBE DESIGN

TOOLS &amp; INFO

- ▼ POGO®CROSS REFERENCE
- ▼ CRIMP PLIERS
- ▼ INSERTION/EXTRACTION
- ▼ PARTS STOCKING SYSTEM
- ▼ POGO MAINTENANCE
- ▼ PROBE HANDLING
- ▼ WIRE WRAPPING

ORDERING

- ▼ ORDERING PRODUCT
- ▼ ORDERING LITERATURE

# Products

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ABOUT ECT

PRODUCTS

RESOURCES

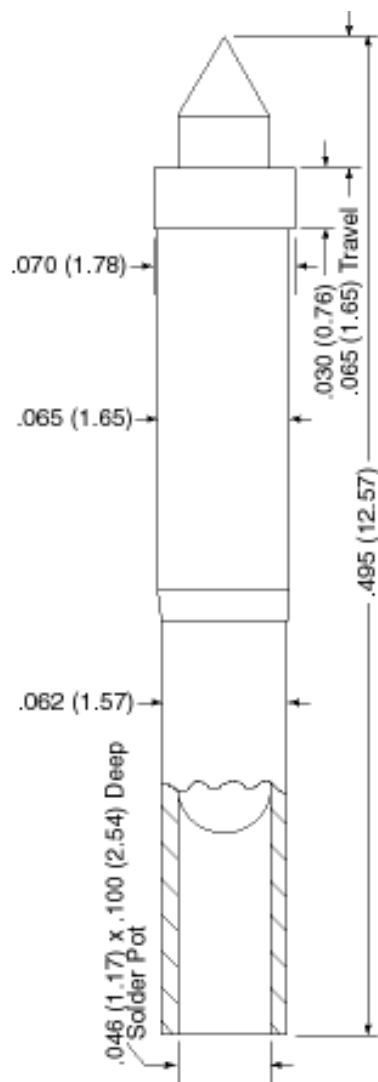
CONTACT US

SITE MAP

SEMICONDUCTOR  
TEST PRODUCTSBARE PCB  
TEST EQUIPMENTLOADED PCB  
TEST FIXTURESPOGO  
CONTACTS

## E-S Series

### Tips



## Probe Specifications

Plunger	Gold-plated hardened BeCu
Body	Gold-plated brass
Spring	Gold-plated BeCu
Ball	Gold-plated stainless steel
Electrical Resistance	< 30 milliohms
Maximum Current	5 amps
Plunger Travel	.065 (1.65)

The recommended hole is .0670 (#51 drill) for epoxy mounting.

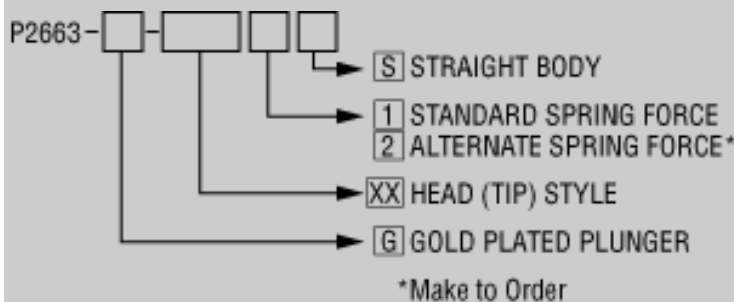
## Spring Force in oz. (grams)

Spring Type	Initial	Working Travel
Standard	1.5 (43)	3.0 (85)

## How to Order [\(top\)](#)

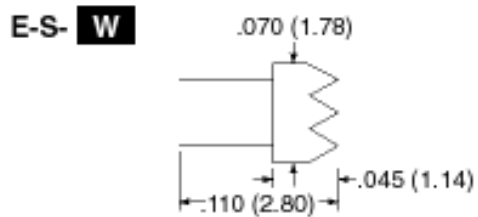
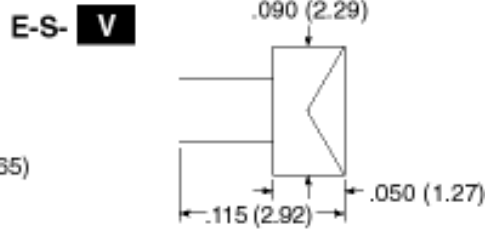
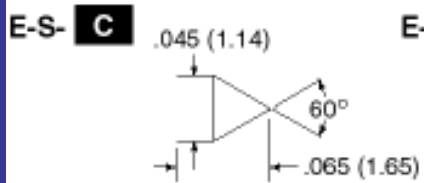
For each probe, specify the probe model and tip style as shown in the example below. If required, specify the optional non-standard spring force.

Example:



## Order Form

## Tips [\(top\)](#)



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## Ordering POGO® Contact Products

Use this form to place an order.

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**To order product:** If you currently have an account with Everett Charles Technologies, and ECT has the correct Ship-to-Information on file, please enter your full name and company in Section 1 and then skip to Section 3 and Section 4.

If you do not have an ECT account, please fill out Section 1 and Section 2 completely, then go to Section 4.

---

### Section 1: Contact Information

Full Name:

Title:

Company:

Postal Address:

City, State and Zip:

Country:

Telephone:

Facsimile:

Email:

---

### Section 2: Shipping Information

Please enter the shipping information only if it differs from the above information.

Ship-To Name:

Company:



<b>Item</b>	<b>Qty.</b>	<b>Part Number</b>	<b>Notes</b>
<b>1</b>			
<b>2</b>			
<b>3</b>			
<b>4</b>			
<b>5</b>			
<b>6</b>			
<b>7</b>			
<b>8</b>			
<b>9</b>			
<b>10</b>			

---

### **Section 5: Information Review**

Please take a moment to review the information you have provided above. If it is correct, please press the SUBMIT button below. Otherwise, please correct the information before submitting. If you would like to have all completed information cleared, press the CLEAR button below.

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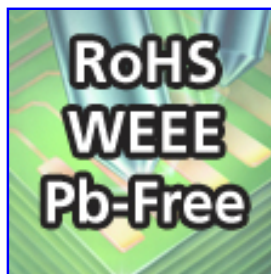


### Battery Interconnect Probes

ECT Contact Products Group' latest versatile line of battery probes gives you the design flexibility to match your performance, cost, and assembly requirements. Our design expertise and complete manufacturing capabilities will help bring your product to market faster and easier. [Learn more.](#)

### Semiconductor POGO® Contacts

ECT Contact Products Group offers a wide array of new probes for semiconductor test. From our Double-Ended probes that come in pitches ranging from .4mm to 1.27 to our unique Mini-Mite™ Single-Ended probes that provide very low, consistent DC resistance, you can bet ECT will meet your semiconductor contact needs. [Learn more.](#)



### PogoPlus® Series Probes

Conventional bias-type probes are susceptible to false opens - that is, transient electrical discontinuities that cause good products to "fail" during test. Revolutionary PogoPlus® probes eliminate probe-induced false opens, saving you the time, money and trouble of needless product retesting.

The PogoPlus® is also designed to be the world's most durable probe with features like optional stainless-steel MicroSharp™ tips, a larger spring volume and enhanced pointing precision.

The unrivaled electrical performance of the PogoPlus® is due to the interaction between the spring, captured ball and plunger, which forces the plunger into continuous contact with the barrel wall at all times. The result is uninterrupted electrical continuity and low overall resistance that can't be equaled by

any other "high performance" probe.